

---

### 0.8% LOW VOLTAGE DETECTOR

---

NO.EA-160-120423

#### OUTLINE

The R3114x series are CMOS-based voltage detector ICs with high detector threshold accuracy and ultra-low supply current, which can be operated at an extremely low voltage and is used for system reset as an example.

Each of these ICs consists of a voltage reference unit, a comparator, resistors for detector threshold setting, an output driver and a hysteresis circuit. The detector threshold is fixed with high accuracy internally and does not require any adjustment.

Two output types, Nch open drain type and CMOS type are available.

The R3114x series are operable at a lower voltage than that of the R3111x series, and can be driven by a single battery.

Three types of packages, SOT-23-5, SC-82AB, and DFN(PLP)1010-4 are available.

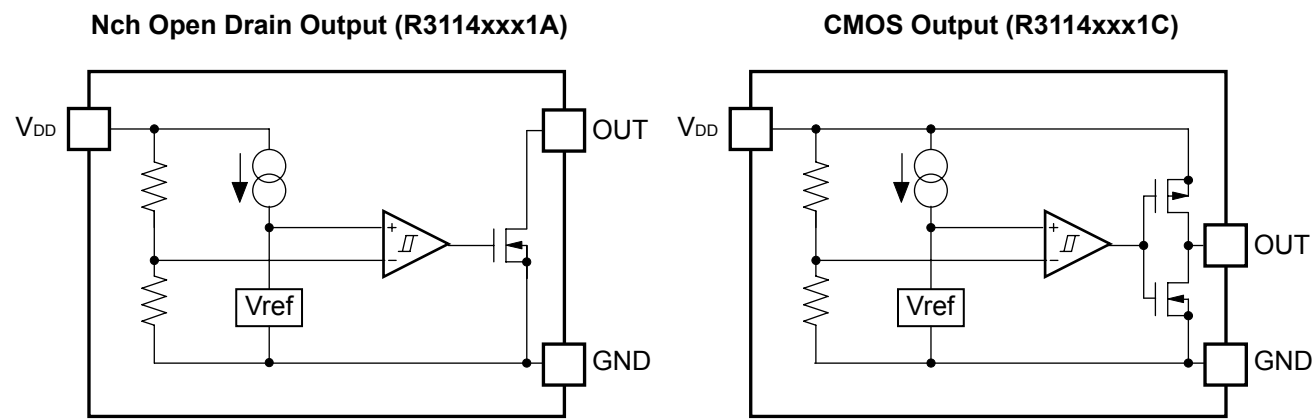
#### FEATURES

- Supply Current ..... Typ. 0.35 $\mu$ A ( $-V_{DET}=1.5V$ ,  $V_{DD}=-V_{DET}+1V$ )
- Operating Voltage Range ..... 0.5V to 6.0V ( $T_{opt}=25^{\circ}C$ )
- Detector Threshold Range ..... 0.7V to 5.0V (0.1V steps)  
(For other voltages, please refer to MARK INFORMATION.)
- Detector Threshold Accuracy .....  $\pm 0.8\%$  ( $-V_{DET} \geq 1.5V$ )
- Temperature-Drift Coefficient of Detector Threshold ..... Typ.  $\pm 30ppm/^{\circ}C$
- Output Types ..... Nch Open Drain "L" and CMOS
- Packages ..... DFN(PLP)1010-4, SC-82AB, SOT-23-5

#### APPLICATIONS

- CPU and Logic Circuit Reset
- Battery Checker
- Window Comparator
- Wave Shaping Circuit
- Battery Back-up Circuit
- Power Failure Detector

BLOCK DIAGRAMS



SELECTION GUIDE

The package type, the detector threshold, the output type and the taping type for the ICs can be selected at the users' request.

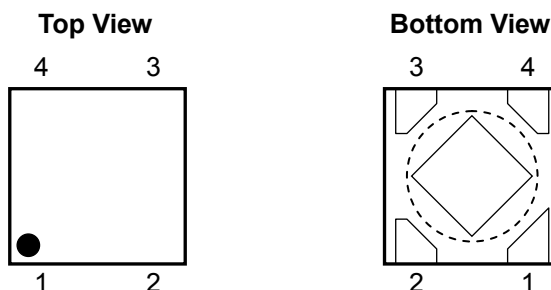
Product Name	Package	Quantity per Reel	Pb Free	Halogen Free
R3114Kxx1*-TR	DFN(PLP)1010-4	10,000 pcs	Yes	Yes
R3114Qxx1*-TR-FE	SC-82AB	3,000 pcs	Yes	Yes
R3114Nxx1*-TR-FE	SOT-23-5	3,000 pcs	Yes	Yes

xx: The detector threshold can be designated in the range from 0.7V(07) to 5.0V(50) in 0.1V steps.  
(For other voltages, please refer to MARK INFORMATION.)

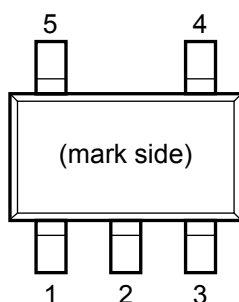
\* : Designation of Output Type  
(A) Nch Open Drain  
(C) CMOS

## PIN CONFIGURATIONS

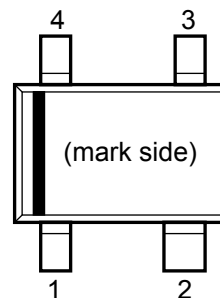
### • DFN(PLP)1010-4\*



### • SOT-23-5



### • SC-82AB



## PIN DESCRIPTIONS

### • DFN(PLP)1010-4\*

Pin No.	Symbol	Description
1	OUT	Output Pin ("L" at detection)
2	NC	No Connection
3	GND	Ground Pin
4	V <sub>DD</sub>	Input Pin

\*) Tab is GND level. (They are connected to the reverse side of this IC.)

The tab is better to be connected to the GND, but leaving it open is also acceptable.

### • SOT-23-5

Pin No.	Symbol	Description
1	OUT	Output Pin ("L" at detection)
2	V <sub>DD</sub>	Input Pin
3	GND	Ground Pin
4	NC	No Connection
5	NC	No Connection

### • SC-82AB

Pin No.	Symbol	Description
1	OUT	Output Pin ("L" at detection)
2	V <sub>DD</sub>	Input Pin
3	NC	No Connection
4	GND	Ground Pin

## ABSOLUTE MAXIMUM RATINGS

Symbol	Item	Rating	Unit
$V_{DD}$	Supply Voltage	7.0	V
$V_{OUT}$	Output Voltage (Nch Open Drain Output)	$V_{SS}-0.3$ to 7.0	V
	Output Voltage (CMOS Output)	$V_{SS}-0.3$ to $V_{DD}+0.3$	
$I_{OUT}$	Output Current	20	mA
$P_D$	Power Dissipation (SOT-23-5)*	420	mW
	Power Dissipation (SC-82AB)*	380	
	Power Dissipation (DFN(PLP)1010-4)*	400	
$T_{opt}$	Operating Temperature Range	-40 to 85	°C
$T_{stg}$	Storage Temperature Range	-55 to 125	°C

\*) For Power Dissipation, please refer to PACKAGE INFORMATION.

### ABSOLUTE MAXIMUM RATINGS

Electronic and mechanical stress momentarily exceeded absolute maximum ratings may cause the permanent damages and may degrade the life time and safety for both device and system using the device in the field.

The functional operation at or over these absolute maximum ratings is not assured.

### RECOMMENDED OPERATING CONDITIONS (ELECTRICAL CHARACTERISTICS)

All of electronic equipment should be designed that the mounted semiconductor devices operate within the recommended operating conditions. The semiconductor devices cannot operate normally over the recommended operating conditions, even if when they are used over such conditions by momentary electronic noise or surge. And the semiconductor devices may receive serious damage when they continue to operate over the recommended operating conditions.

## ELECTRICAL CHARACTERISTICS

• R3114xxx1A/C   values indicate  $-40^{\circ}\text{C} \leq T_{\text{opt}} \leq 85^{\circ}\text{C}$ , unless otherwise noted.  $T_{\text{opt}}=25^{\circ}\text{C}$

Symbol	Item	Conditions		Min.	Typ.	Max.	Unit
$-V_{\text{DET}}$	Detector Threshold	$T_{\text{opt}}=25^{\circ}\text{C}$	$1.5\text{V} < -V_{\text{DET}} \leq 5.0\text{V}$	$-V_{\text{DET}} \times 0.992$		$-V_{\text{DET}} \times 1.008$	V
			$0.7\text{V} \leq -V_{\text{DET}} \leq 1.5\text{V}$	-12		+12	mV
		$-40^{\circ}\text{C} \leq T_{\text{opt}} \leq 85^{\circ}\text{C}$	$1.5\text{V} < -V_{\text{DET}} \leq 5.0\text{V}$	$-V_{\text{DET}} \times 0.985$		$-V_{\text{DET}} \times 1.015$	V
			$0.7\text{V} \leq -V_{\text{DET}} \leq 1.5\text{V}$	-22.5		+22.5	mV
$V_{\text{HYS}}$	Detector Threshold Hysteresis			$-V_{\text{DET}} \times 0.04$		$-V_{\text{DET}} \times 0.07$	V
$I_{\text{SS}}$	Supply Current	$V_{\text{DD}}=-V_{\text{DET}}-0.1\text{V}$	$0.7\text{V} \leq -V_{\text{DET}} < 1.6\text{V}$			1.40	$\mu\text{A}$
			$1.6\text{V} \leq -V_{\text{DET}} < 3.1\text{V}$			1.50	
			$3.1\text{V} \leq -V_{\text{DET}} < 4.1\text{V}$			1.60	
			$4.1\text{V} \leq -V_{\text{DET}} \leq 5.0\text{V}$			1.70	
		$V_{\text{DD}}=-V_{\text{DET}}+0.1\text{V}$	$0.7\text{V} \leq -V_{\text{DET}} < 1.6\text{V}$			1.20	
			$1.6\text{V} \leq -V_{\text{DET}} < 3.1\text{V}$			1.20	
			$3.1\text{V} \leq -V_{\text{DET}} < 4.1\text{V}$			1.30	
			$4.1\text{V} \leq -V_{\text{DET}} \leq 5.0\text{V}$			1.40	
$V_{\text{DDH}}$	Maximum Operating Voltage					6	V
$V_{\text{DDL}}$	Minimum Operating Voltage*1	$T_{\text{opt}}=25^{\circ}\text{C}$				0.50	V
		$-40^{\circ}\text{C} \leq T_{\text{opt}} \leq 85^{\circ}\text{C}$				0.55	V
$I_{\text{OUT}}$	Output Current (Driver Output Pin)	Nch	$V_{\text{DD}}=0.55\text{V}, V_{\text{DS}}=0.05\text{V}$	7			$\mu\text{A}$
			$0.7\text{V} \leq -V_{\text{DET}} < 1.1\text{V}$ $V_{\text{DD}}=0.6\text{V}$ $V_{\text{DS}}=0.5\text{V}$	0.02			mA
			$1.1\text{V} \leq -V_{\text{DET}} < 1.6\text{V}$ $V_{\text{DD}}=1.0\text{V}$ $V_{\text{DS}}=0.5\text{V}$	0.40			
			$1.6\text{V} \leq -V_{\text{DET}} < 3.1\text{V}$ $V_{\text{DD}}=1.5\text{V}$ $V_{\text{DS}}=0.5\text{V}$	1.00			
			$3.1\text{V} \leq -V_{\text{DET}} \leq 5.0\text{V}$ $V_{\text{DD}}=3.0\text{V}$ $V_{\text{DS}}=0.5\text{V}$	2.40			
		Pch*2	$0.7\text{V} \leq -V_{\text{DET}} < 4.0\text{V}$ $V_{\text{DD}}=4.5\text{V}$ $V_{\text{DS}}=-2.1\text{V}$	0.65			mA
			$4.0\text{V} \leq -V_{\text{DET}} \leq 5.0\text{V}$ $V_{\text{DD}}=6.0\text{V}$ $V_{\text{DS}}=-2.1\text{V}$	0.90			
$I_{\text{LEAK}}$	Nch Driver Leakage Current*3	$V_{\text{DD}}=6.0\text{V}, V_{\text{DS}}=7.0\text{V}$				80	nA
$\Delta V_{\text{DET}} / \Delta T_{\text{opt}}$	Detector Threshold Temperature Coefficient				$\pm 30$		ppm/ $^{\circ}\text{C}$
$t_{\text{PLH}}$	Output Delay Time	$V_{\text{DD}}=0.55\text{V}$ to $-V_{\text{DET}}+2.0\text{V}$ or $6.0\text{V}$			40		$\mu\text{s}$

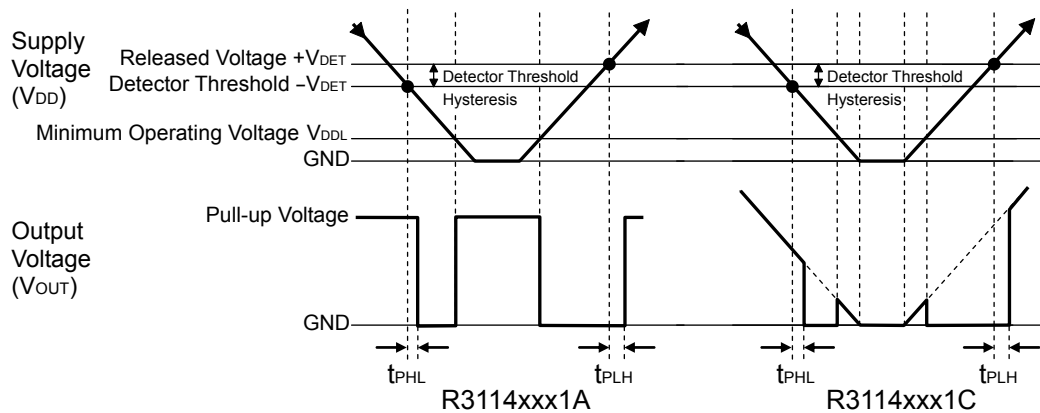
All of unit are tested and specified under load conditions such that  $T_{\text{opt}}=25^{\circ}\text{C}$  except for Detector Threshold Temperature Coefficient.

\*1: Minimum operating voltage means the value of input voltage when output voltage maintains 0.1V or less.  
(In case of Nch Open Drain Output type, the output pin is pulled up with a resistance of 470k $\Omega$  to 5.0V)

\*2: In case of CMOS type

\*3: In case of Nch Open Drain type

## TIMING CHART



## DEFINITION OF OUTPUT DELAY TIME

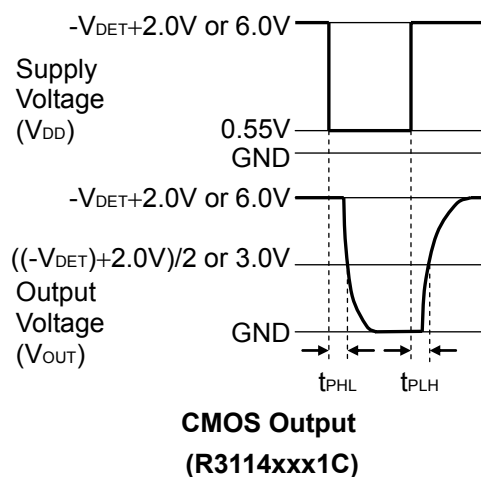
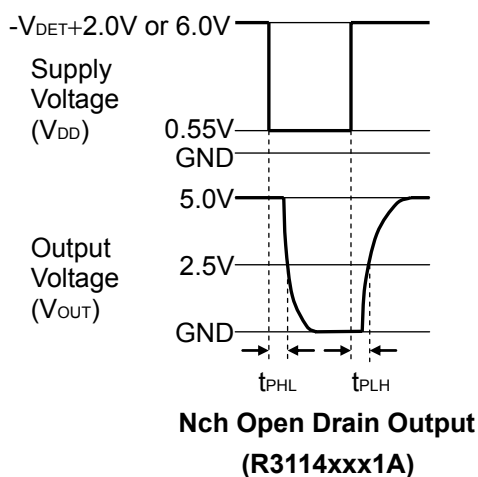
Output Delay Time ( $t_{PLH}$ ) is defined as follows:

1. In the case of Nch Open Drain Output:

Under the condition of the output pin (OUT) is pulled up through a resistor of 470k $\Omega$  to 5V, the time interval between the rising edge of  $V_{DD}$  pulse from 0.55V to  $(-V_{DET}) + 2.0V$  or the time interval of 6.0V pulse voltage is supplied, the becoming of the output voltage to 2.5V.

2. In the case of CMOS Output:

The time interval between the rising edge of  $V_{DD}$  pulse from 0.55V to  $(-V_{DET}) + 2.0V$  or the time interval of 6.0V pulse voltage is supplied, the becoming of the output voltage to  $((-V_{DET}) + 2.0V) / 2$  or 3.0V.





Nch Driver Output Current1		Nch Driver Output Current2		Pch Driver Output Current		Nch Driver Leakage Current		Detector Threshold Temperature Coefficient	Output Delay Time	
IOUT1 [ $\mu$ A]		IOUT2 [mA]		IOUT3 [mA]		ILEAK [nA]		$\Delta V_{DET}/\Delta T_{opt}$ [ppm/ $^{\circ}$ C]	tPLH [ $\mu$ s]	
Cond.	Min.	Cond.	Min.	Cond.	Min.	Cond.	Max.	Typ.	Cond.	Typ.
VDD= 0.55V  VDS= 0.05V	7	VDD= 0.6V VDS= 0.5V	0.020	VDD= 4.5V  VDS= -2.1V	0.650	VDD= 6.0V  VDS= 7.0V	80	$\pm 30$	VDD= 0.55V ↓ -VDET +2.0V *Note2	40
		VDD= 1.0V  VDS= 0.5V	0.400							
		VDD= 1.5V  VDS= 0.5V	1.000							
		VDD= 3.0V  VDS= 0.5V	2.400	VDD= 6.0V  VDS= -2.1V	0.900				VDD= 0.55V ↓ 6.0V *Note2	

\*Note2) 1. In the case of CMOS output type:

When the voltage is forced from 0.55V to  $(-V_{DET})+2.0V$  or a 6.0V pulse voltage is added to VDD, time interval that the output voltage reaches  $((-V_{DET})+2.0V)/2$  or a 3.0V.

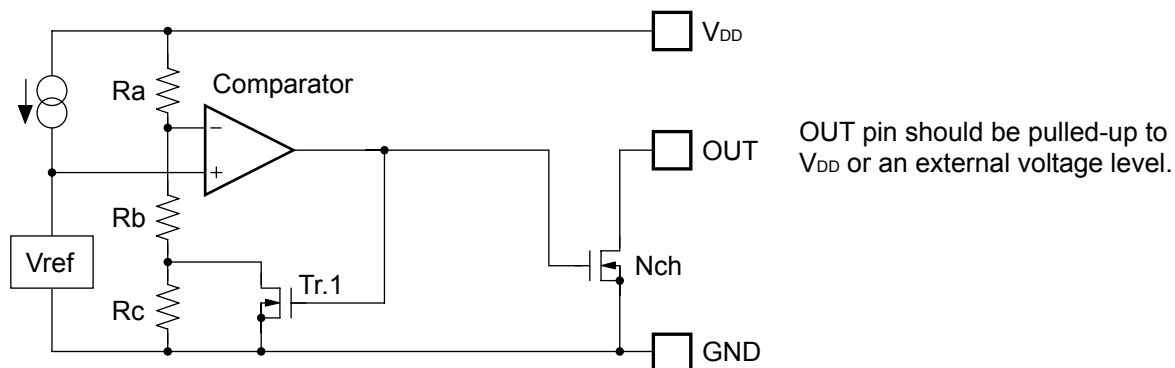
2. In the case of Nch Open Drain output type:

The output pin is pulled up to 5.0V through 470k $\Omega$ , and when the voltage is forced from 0.55V to  $(-V_{DET})+2.0V$  or a 6.0V pulse voltage is added to VDD, time interval that the output voltage reaches 2.5V.

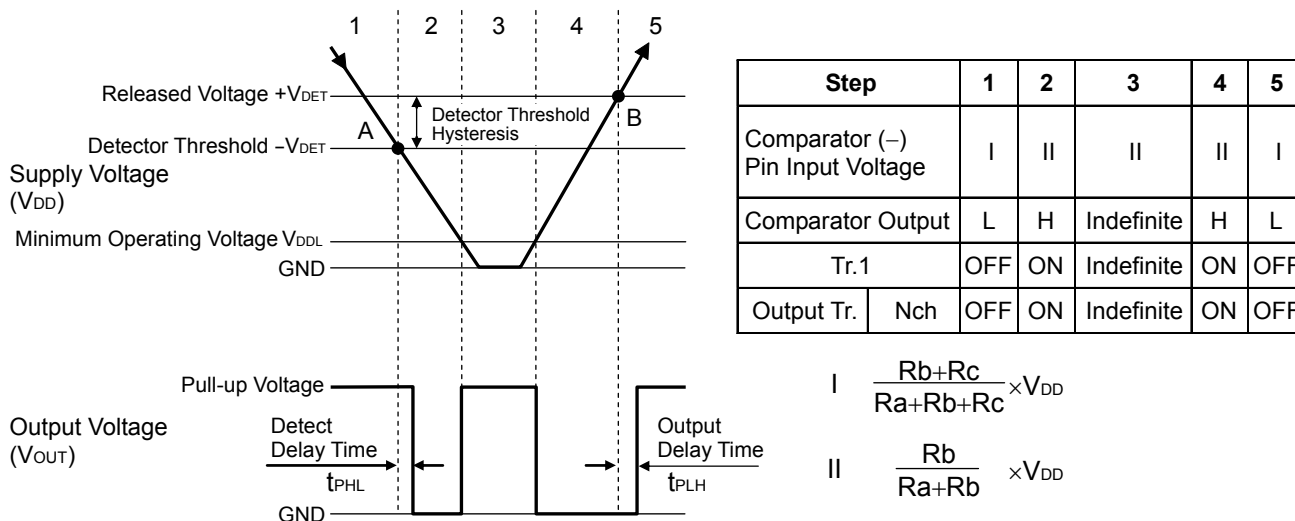


## OPERATION

- **Operation of R3114xxx1A**



### Block Diagram (R3114xxx1A)



- **Explanation of operation**

Step 1. The output voltage is equal to the pull-up voltage.

Step 2. At Point "A",  $V_{ref} \geq V_{DD} \times (R_b + R_c) / (R_a + R_b + R_c)$  is true, as a result, the output of comparator is reversed from "L" to "H", therefore the output voltage becomes the GND level. The voltage level of Point A means a detector threshold voltage ( $-V_{DET}$ ).

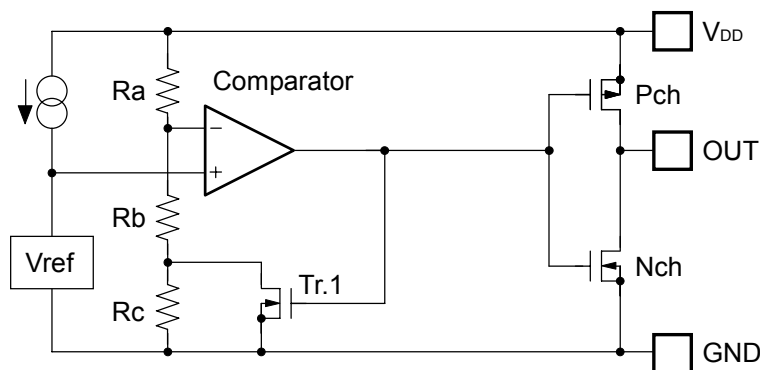
Step 3. When the supply voltage is lower than the minimum operating voltage, the operation of the output transistor becomes indefinite. The output voltage is equal to the pull-up voltage.

Step 4. The output voltage is equal to the GND level.

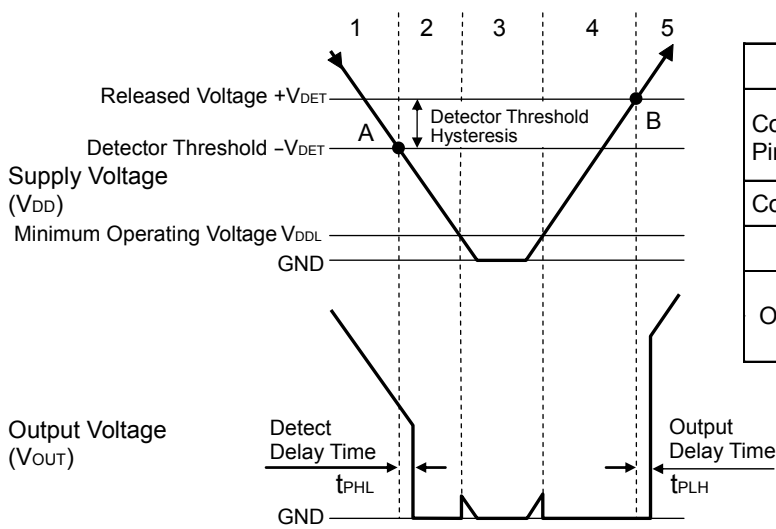
Step 5. At Point "B",  $V_{ref} \leq V_{DD} \times R_b / (R_a + R_b)$  is true, as a result, the output of comparator is reversed from "H" to "L", then the output voltage is equal to the pull-up voltage. The voltage level of Point B means a released voltage ( $+V_{DET}$ ).

\*) The difference between a released voltage and a detector threshold voltage is a detector threshold hysteresis.

• Operation of R3114xxx1C



Block Diagram (R3114xxx1C)



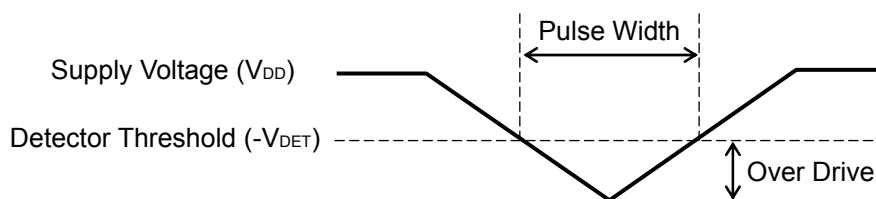
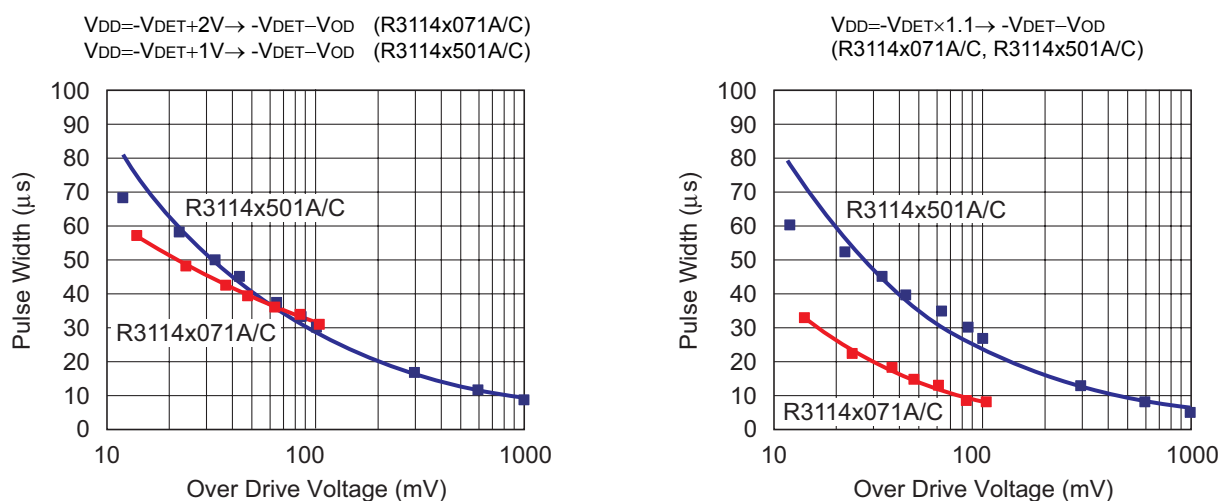
Operation Diagram

• Explanation of operation

- Step 1. The output voltage is equal to the supply voltage ( $V_{DD}$ ).
- Step 2. At Point "A",  $V_{ref} \geq V_{DD} \times (R_b+R_c)/(R_a+R_b+R_c)$  is true, as a result, the output of comparator is reversed from "L" to "H", therefore the output voltage becomes the GND level. The voltage level of Point A means a detector threshold voltage ( $-V_{DET}$ ).
- Step 3. When the supply voltage is lower than the minimum operating voltage, the operation of the output transistor becomes indefinite.
- Step 4. The output voltage is equal to the GND level.
- Step 5. At Point "B",  $V_{ref} \leq V_{DD} \times R_b/(R_a+R_b)$  is true, as a result, the output of comparator is reversed from "H" to "L", then the output voltage is equal to the supply voltage ( $V_{DD}$ ). The voltage level of Point B means a released voltage ( $+V_{DET}$ ).
- \*) The difference between a released voltage and a detector threshold voltage is a detector threshold hysteresis.

## Detector Operation vs. glitch input voltage to the V<sub>DD</sub> pin

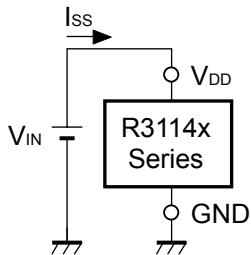
When the R3114x is at released, if the pulse voltage which the detector threshold or lower voltage, the graph below means that the relation between pulse width and the amplitude of the swing to keep the released state for the R3114x.



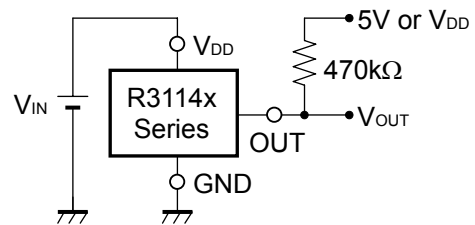
**V<sub>DD</sub> Input Waveform**

This graph shows the maximum pulse conditions to keep the released voltage. If the pulse with larger amplitude or wider width than the graph above, is input to V<sub>DD</sub> pin, the reset signal may be output.

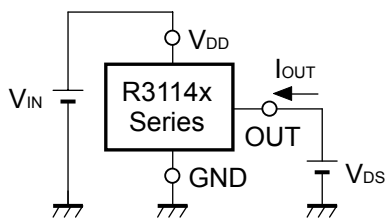
## TEST CIRCUITS



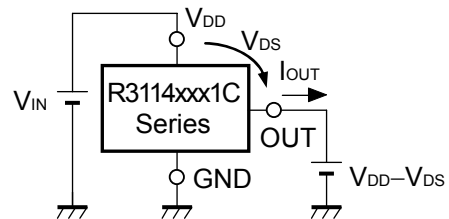
**Supply Current Test Circuit**



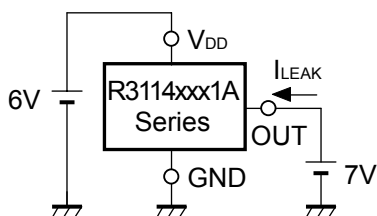
**Detector Threshold Test Circuit**  
(Pull-up circuit is not necessary for CMOS Output type.)



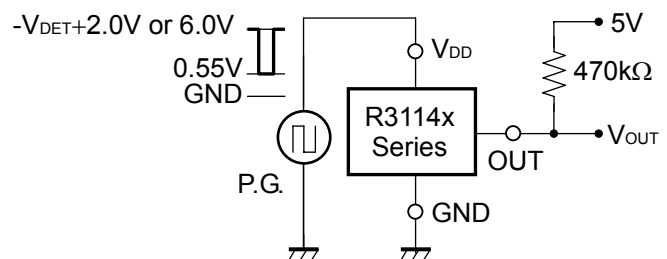
**Nch Driver Output Current Test Circuit**



**Pch Driver Output Current Test Circuit**  
\*Apply to CMOS Output type only



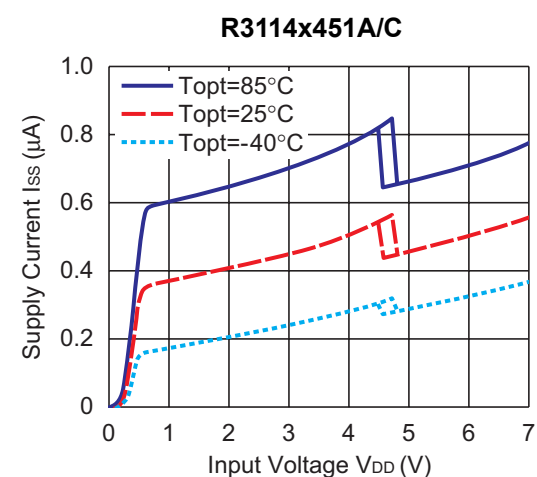
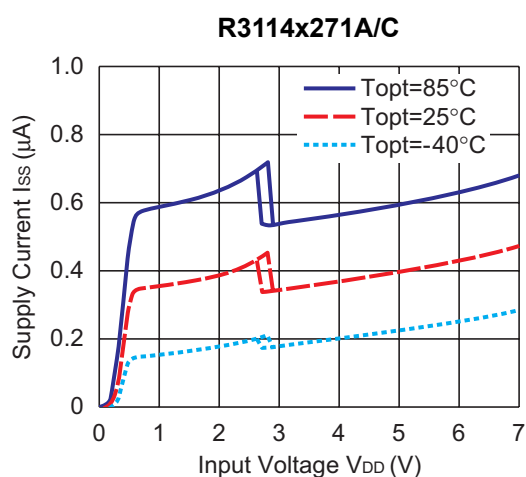
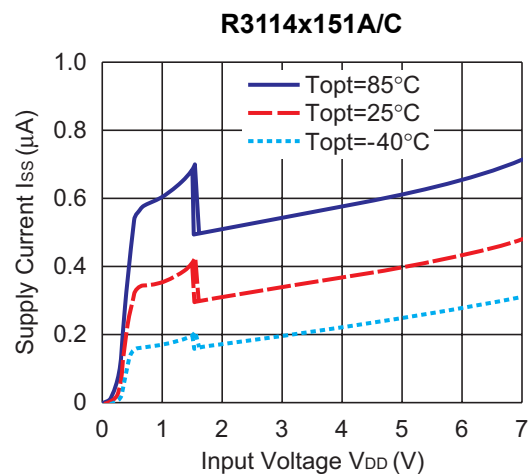
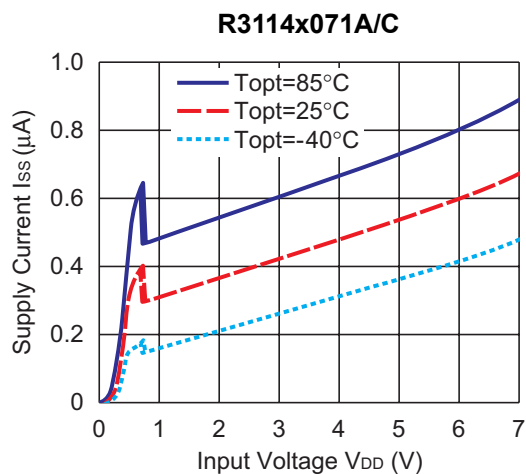
**Nch Driver Leakage Current Test Circuit**  
\*Apply to Nch Driver Output type only



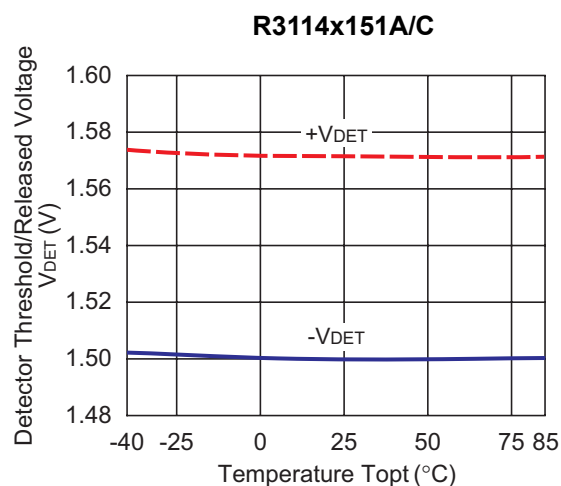
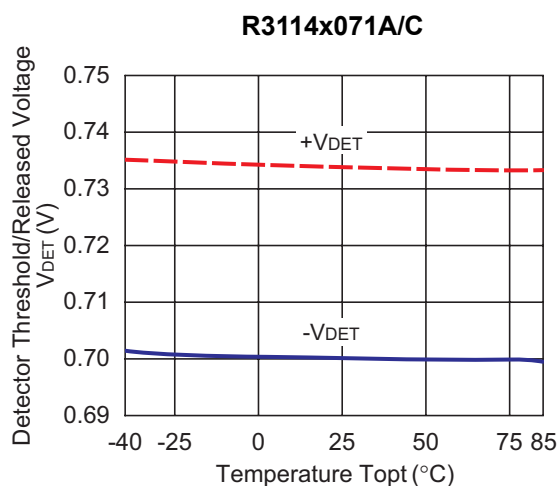
**Output Delay Time Test Circuit**  
(Pull-up circuit is not necessary for CMOS Output type.)

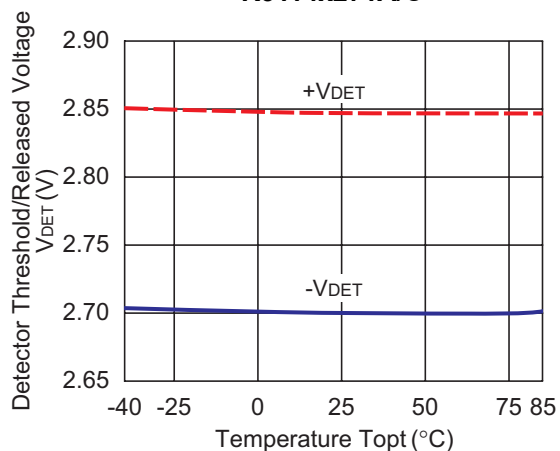
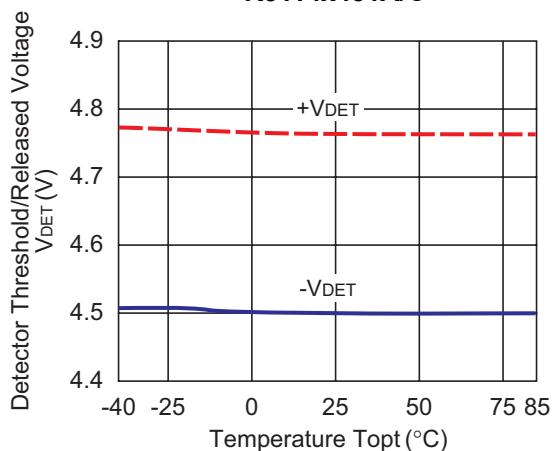
## TYPICAL CHARACTERISTICS

### 1) Supply Current vs. Input Voltage

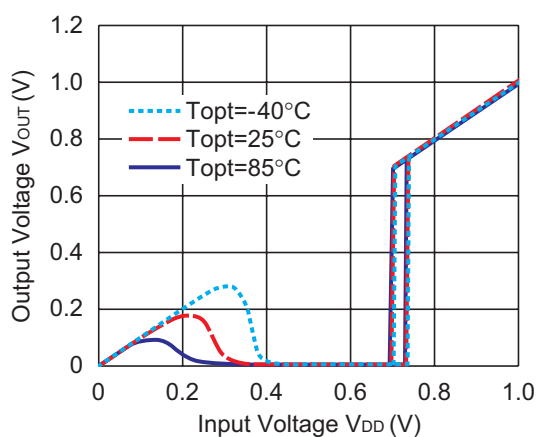
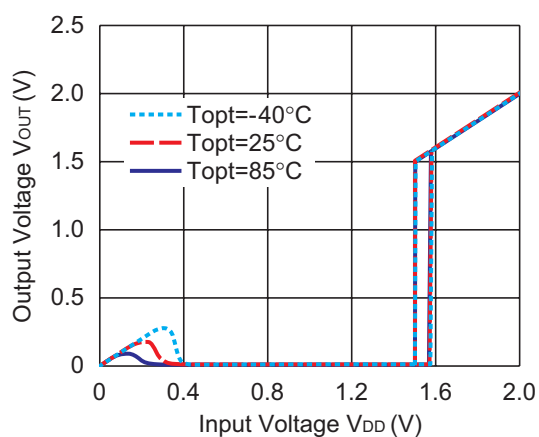
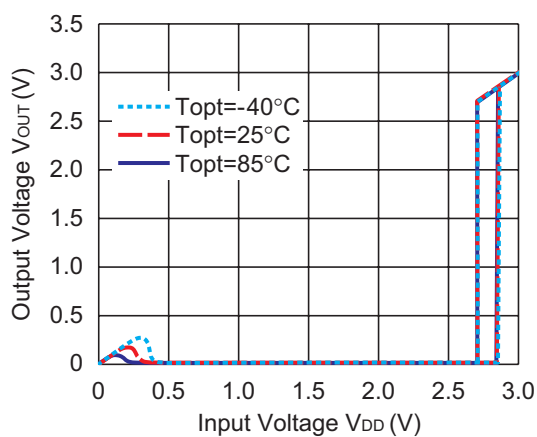
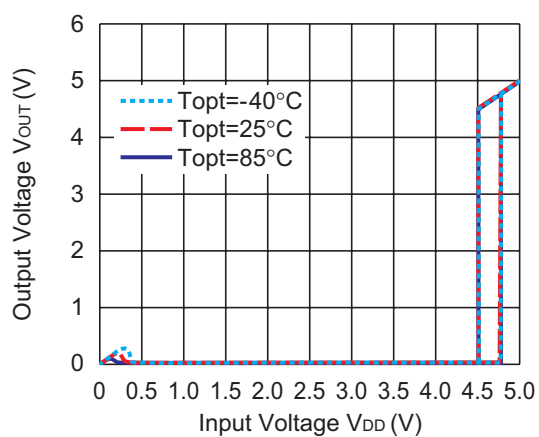


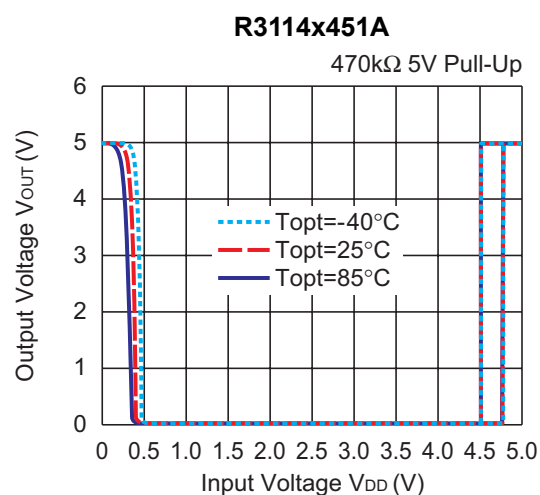
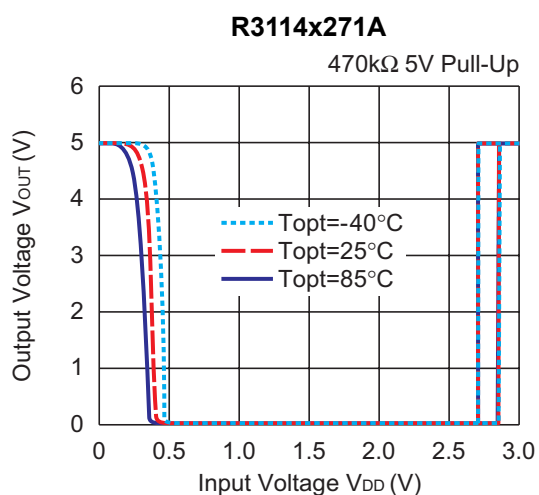
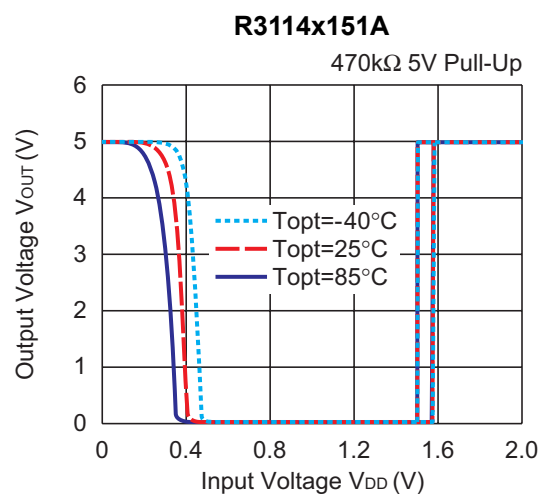
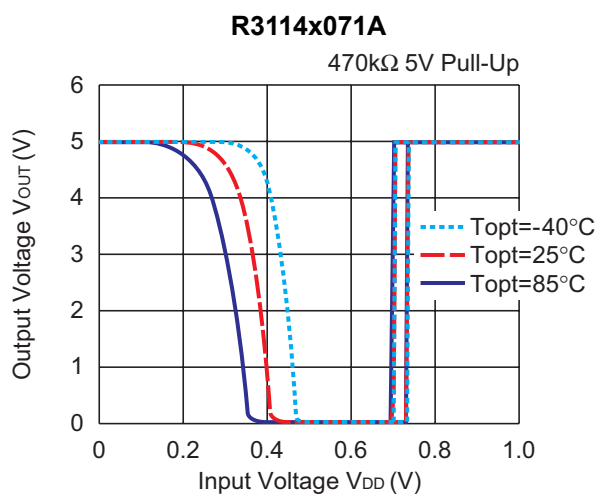
### 2) Detector Threshold vs. Temperature



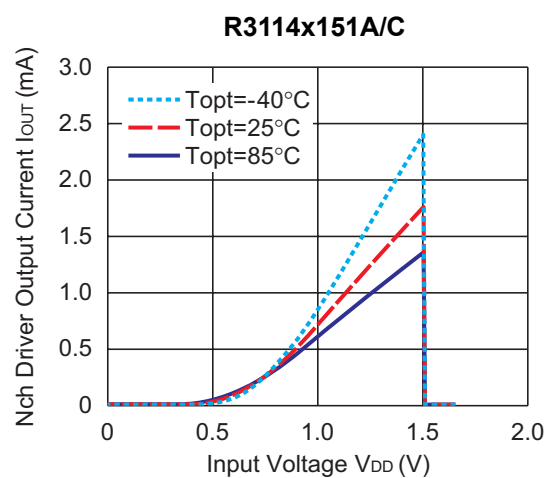
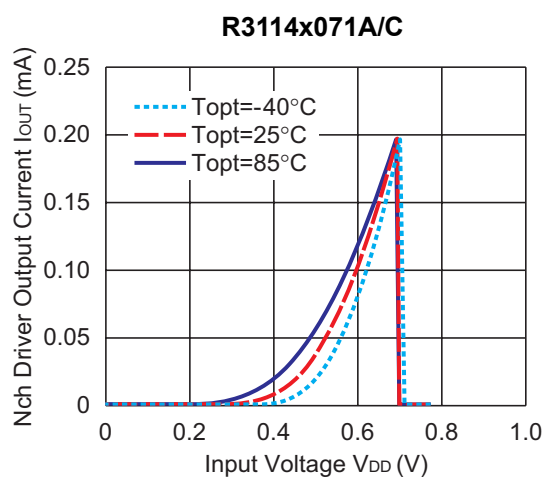
**R3114x271A/C**

**R3114x451A/C**


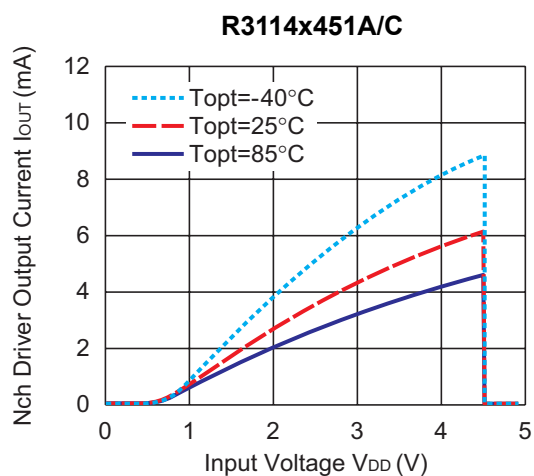
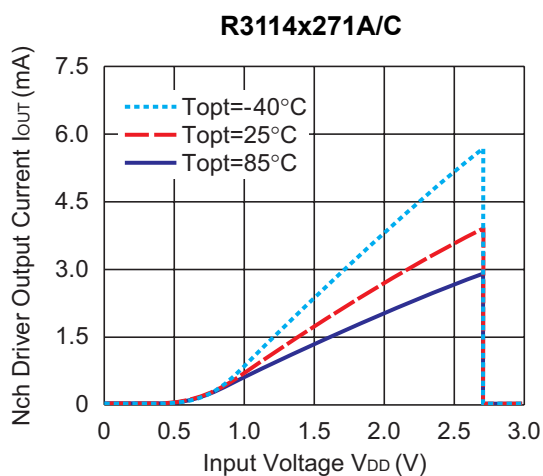
### 3) Output Voltage vs. Input Voltage

**R3114x071C**

**R3114x151C**

**R3114x271C**

**R3114x451C**


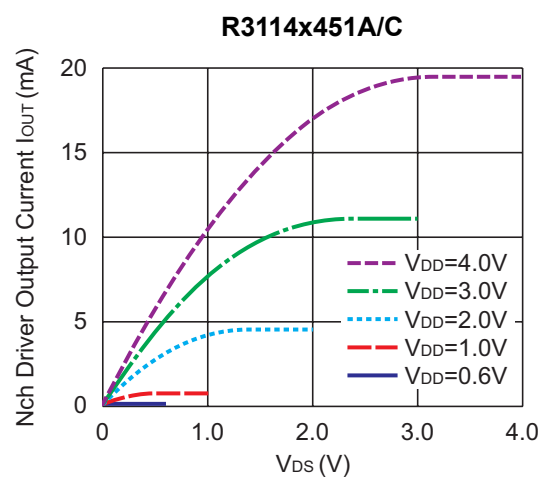
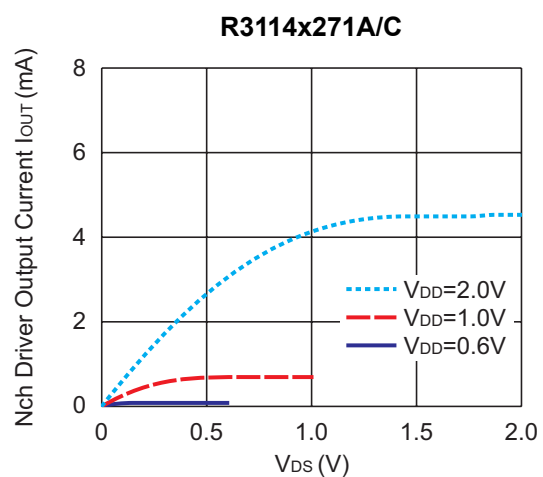
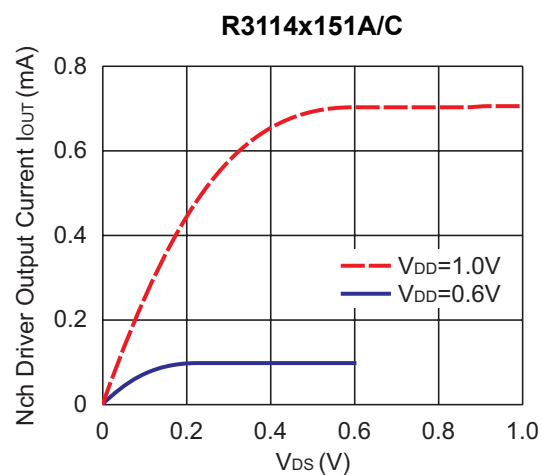
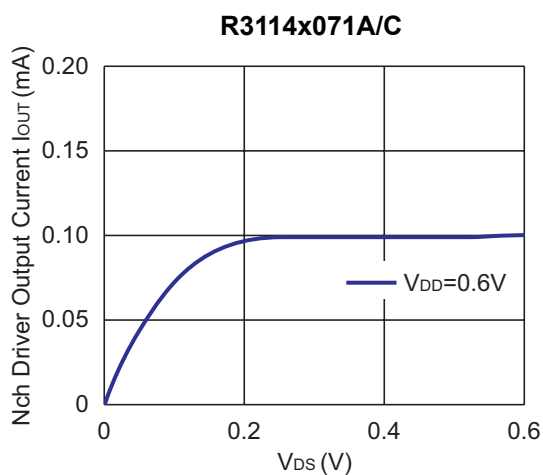


#### 4) Nch Driver Output Current vs. Input Voltage ( $V_{DS}=0.5\text{V}$ )



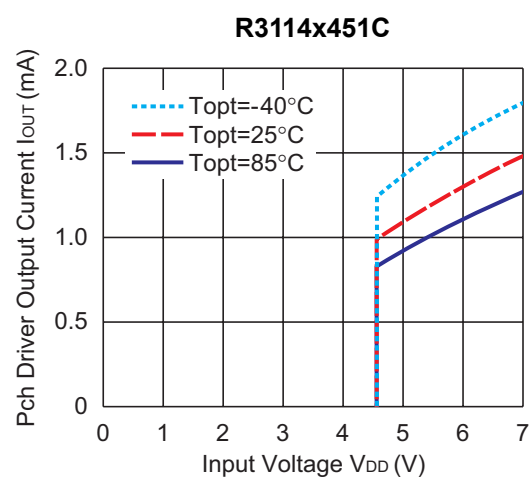
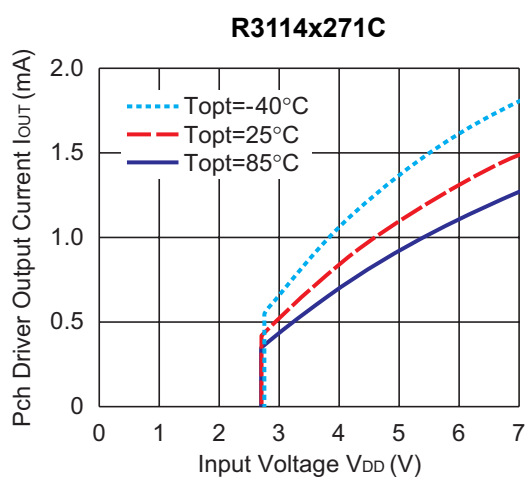
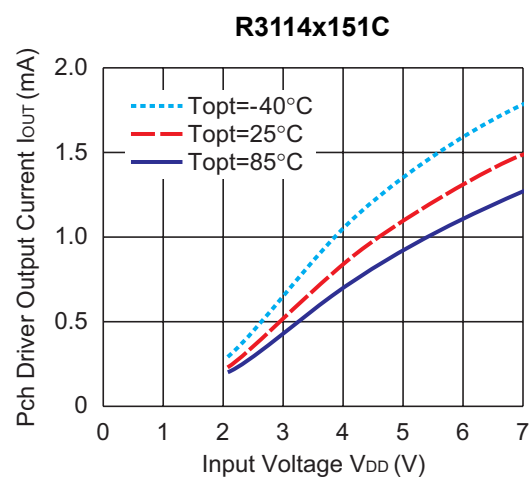
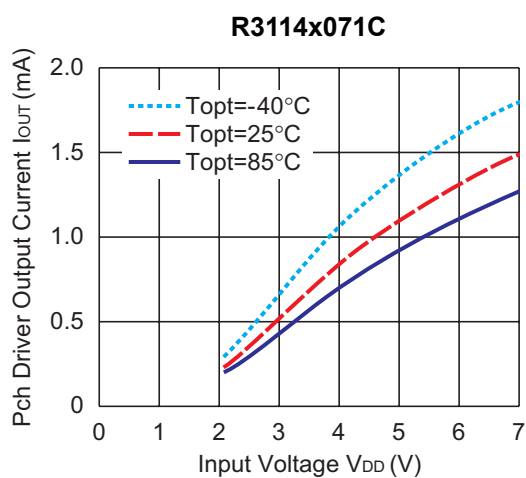


### 5) Nch Driver Output Current vs. $V_{DS}$

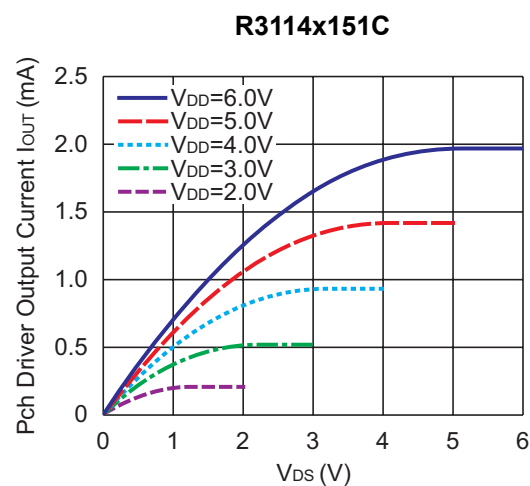
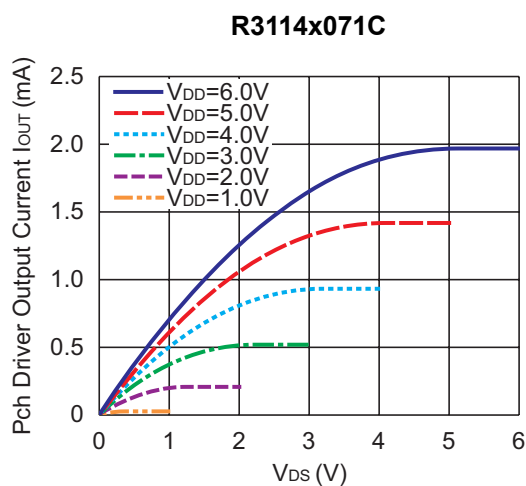




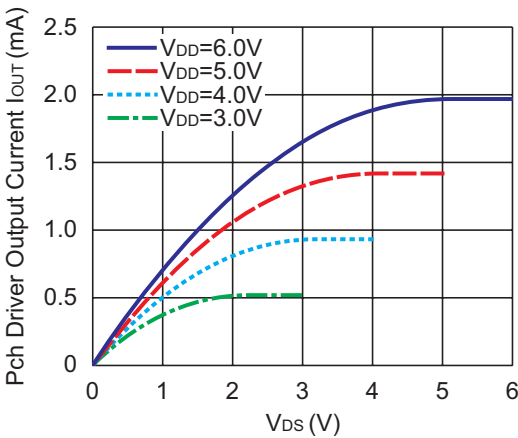
## 6) Pch Driver Output Current vs. Input Voltage ( $V_{DS} = -2.1V$ )



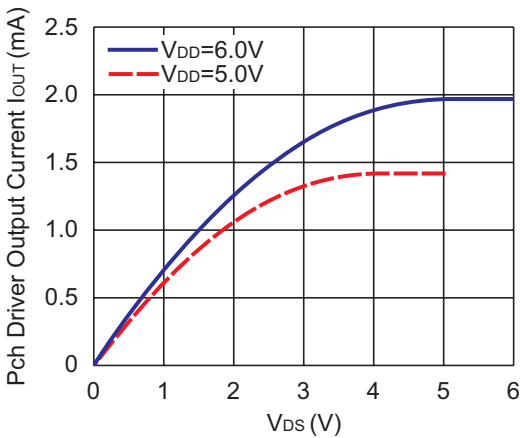
## 7) Pch Driver Output Current vs. $V_{DS}$



R3114x271C

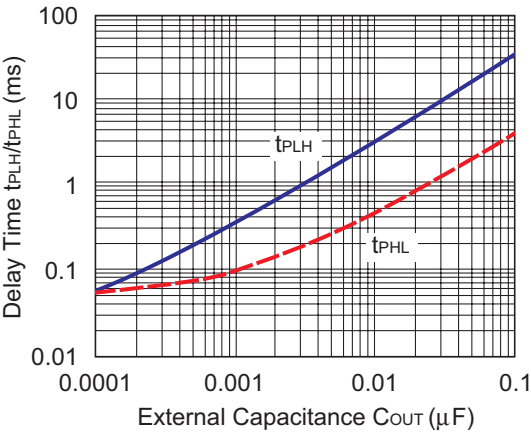


R3114x451C

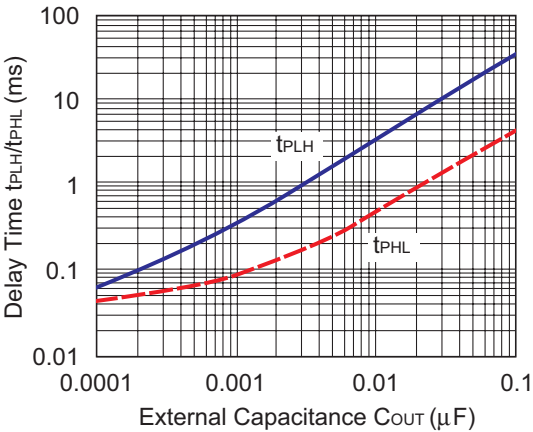


8) Output Delay Time vs. External Capacitance

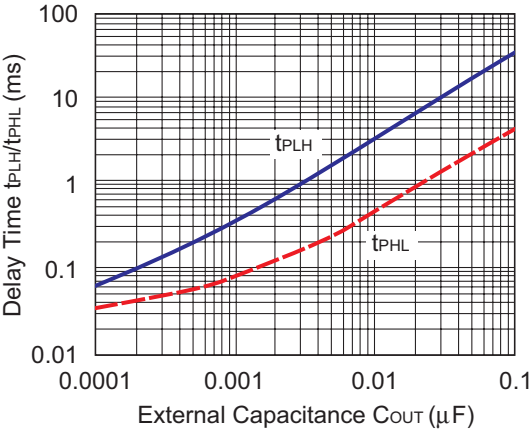
R3114x071A



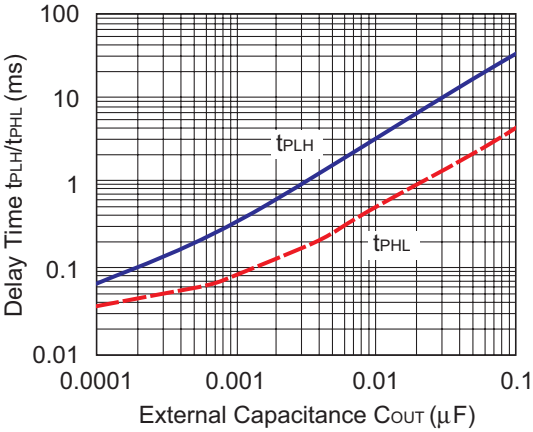
R3114x151A



R3114x271A



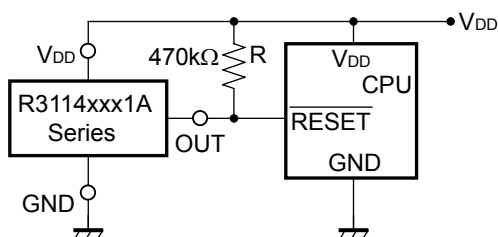
R3114x451A



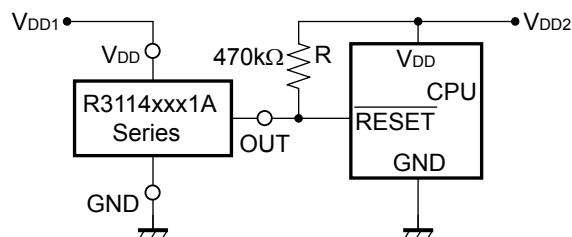
## TYPICAL APPLICATION

### • R3114xxx1A CPU Reset Circuit 1 (Nch Open Drain Output)

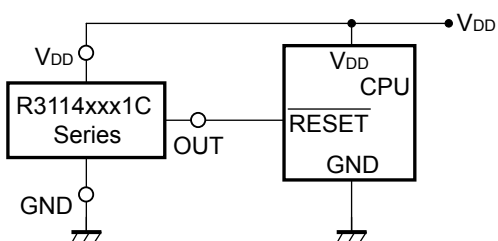
Case1. Input Voltage to R3114xxx1A is equal to Input Voltage to CPU



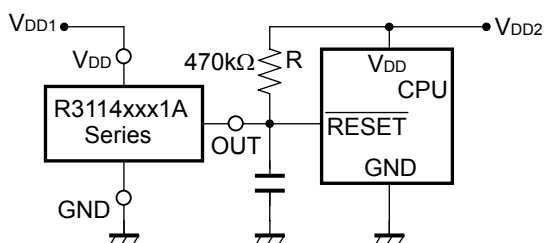
Case2. Input Voltage to R3114xxx1A is unequal to Input Voltage to CPU



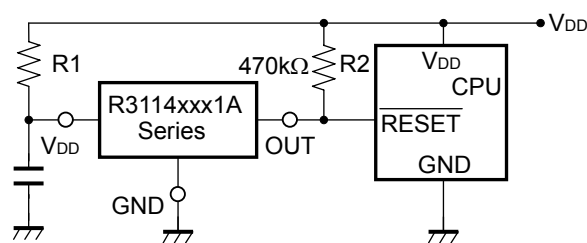
### • R3114xxx1C CPU Reset Circuit (CMOS Output)



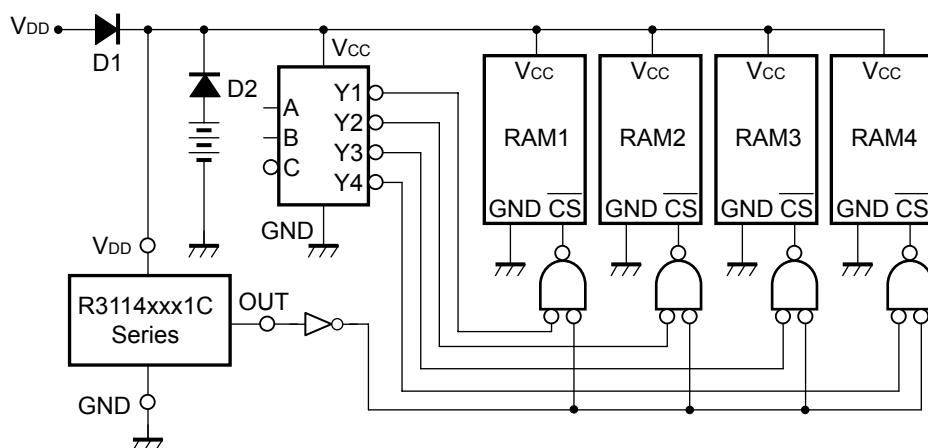
### • R3114xxx1A Output Delay Time Circuit 1 (Nch Open Drain Output)



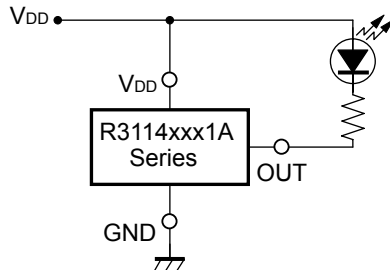
### • R3114xxx1A Output Delay Time Circuit 2 (Nch Open Drain Output)



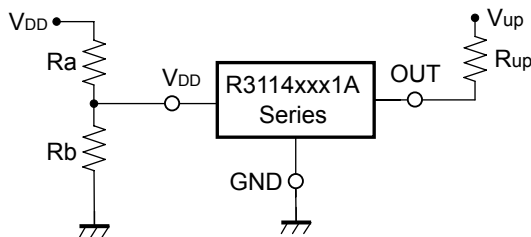
### • Memory Back-up Circuit



- **Voltage level Indicator Circuit (lighted when the power runs out)**  
(Nch Open Drain Output)



- **Detector Threshold Adjustable Circuit 1**  
(Nch Open Drain Output)

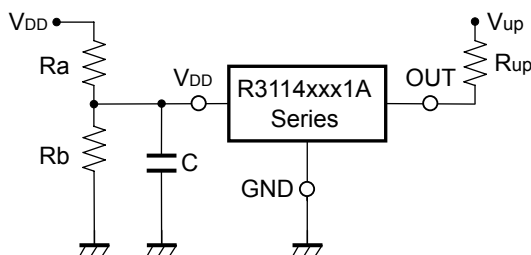


$$\text{Adjustable Detector Threshold} = (-V_{\text{DET}}) \times (R_a + R_b) / R_b$$

$$\text{Hysteresis Voltage} = (V_{\text{HYS}}) \times (R_a + R_b) / R_b$$

- \*1) To prevent oscillation, set  $R_a \leq 1\text{k}\Omega$ ,  $R_b \leq 100\Omega$ .
- \*2) If the value of  $R_a$  is set excessively large, voltage drop may occur caused by the supply current of IC itself, and detector threshold and hysteresis voltage may vary.
- \*3) If  $V_{\text{up}}$  and  $V_{\text{DD}}$  are connected, the voltage dropdown caused by  $R_{\text{up}}$ , may cause difference in the hysteresis voltage.

- **Detector Threshold Adjustable Circuit 2**  
(Nch Open Drain Output)

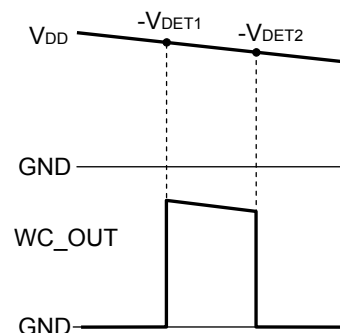
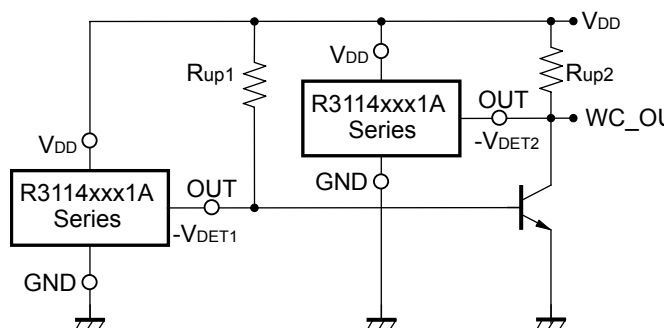


$$\text{Adjustable Detector Threshold} = (-V_{\text{DET}}) \times (R_a + R_b) / R_b$$

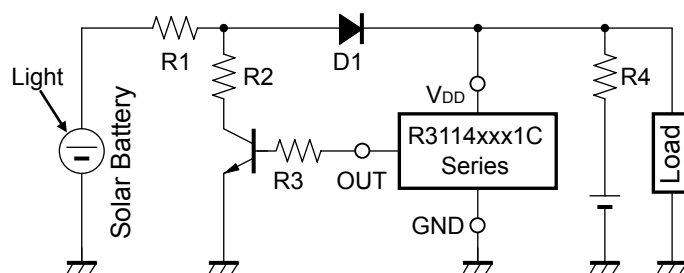
$$\text{Hysteresis Voltage} = (V_{\text{HYS}}) \times (R_a + R_b) / R_b$$

- \*1) To prevent oscillation, set  $R_a \leq 100\text{k}\Omega$ ,  $C \geq 0.01\mu\text{F}$ .
- \*2) If the value of  $R_a$  is set excessively large, voltage drop may occur caused by the supply current of IC itself, and detector threshold and hysteresis voltage may vary.
- \*3) If  $V_{\text{up}}$  and  $V_{\text{DD}}$  are connected, the voltage dropdown caused by  $R_{\text{up}}$ , may cause difference in the hysteresis voltage.
- \*4) If the value of  $R_a$ ,  $R_b$  and  $C$  are set excessively large, the delay of the start-up may become too long.

- **Window Comparator Circuit  
(Nch Open Drain Output)**



- **Over-charge Preventing Circuit**

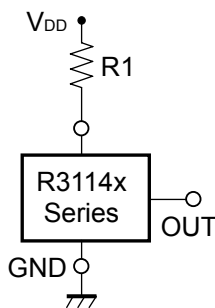


## TECHNICAL NOTES

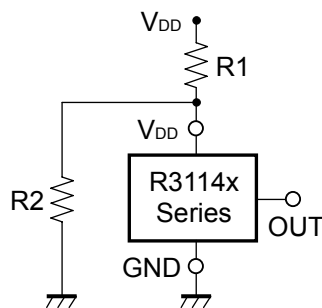
When R3114xxx1A/C is used in Figure X, if the value of R1 is set excessively large, the dropdown voltage caused by the consumption current of IC itself, may vary the detector threshold and the release voltage. Also, if the value of R1 is set excessively large, there may be delay in start-up and may cause oscillation generated by cross conduction current.

When R3114xxx1A/C is used in Figure Y, if the value of R1 is set excessively large, the dropdown voltage caused by the consumption current of IC itself, may vary the detector threshold and the released voltage. Also, if the value of R1 and R2 is set excessively large, there may be delay in start-up and may cause oscillation generated by cross conduction current.

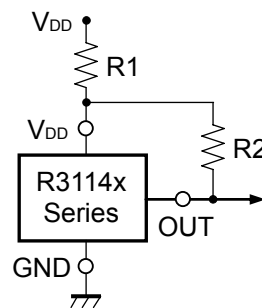
When R3114xxx1A/C is used in Figure Z, if the value of R1 is set excessively large, the dropdown voltage caused by the consumption current of IC itself may vary the detector threshold and the release voltage. Also, if the value of R1 is set excessively large, there may be delay in start-up and may cause oscillation generated by cross conduction current. Furthermore, if the value of R1 is set large and the value of R2 is set small, released voltage level may shift and the minimum operating voltage may differ. If the value of R2 is set excessively small from R1, release may not occur and may cause oscillation.



**Figure X**



**Figure Y**



**Figure Z**



1. The products and the product specifications described in this document are subject to change or discontinuation of production without notice for reasons such as improvement. Therefore, before deciding to use the products, please refer to Ricoh sales representatives for the latest information thereon.
2. The materials in this document may not be copied or otherwise reproduced in whole or in part without prior written consent of Ricoh.
3. Please be sure to take any necessary formalities under relevant laws or regulations before exporting or otherwise taking out of your country the products or the technical information described herein.
4. The technical information described in this document shows typical characteristics of and example application circuits for the products. The release of such information is not to be construed as a warranty of or a grant of license under Ricoh's or any third party's intellectual property rights or any other rights.
5. The products listed in this document are intended and designed for use as general electronic components in standard applications (office equipment, telecommunication equipment, measuring instruments, consumer electronic products, amusement equipment etc.). Those customers intending to use a product in an application requiring extreme quality and reliability, for example, in a highly specific application where the failure or misoperation of the product could result in human injury or death (aircraft, spacevehicle, nuclear reactor control system, traffic control system, automotive and transportation equipment, combustion equipment, safety devices, life support system etc.) should first contact us.
6. We are making our continuous effort to improve the quality and reliability of our products, but semiconductor products are likely to fail with certain probability. In order to prevent any injury to persons or damages to property resulting from such failure, customers should be careful enough to incorporate safety measures in their design, such as redundancy feature, firecontainment feature and fail-safe feature. We do not assume any liability or responsibility for any loss or damage arising from misuse or inappropriate use of the products.
7. Anti-radiation design is not implemented in the products described in this document.
8. Please contact Ricoh sales representatives should you have any questions or comments concerning the products or the technical information.

## RICOH COMPANY, LTD. Electronic Devices Company



■ Ricoh presented with the Japan Management Quality Award for 1999.  
Ricoch continually strives to promote customer satisfaction, and shares the achievements of its management quality improvement program with people and society.



■ Ricoh awarded ISO 14001 certification.

The Ricoh Group was awarded ISO 14001 certification, which is an international standard for environmental management systems, at both its domestic and overseas production facilities. Our current aim is to obtain ISO 14001 certification for all of our business offices.

<http://www.ricoh.com/LSI/>

### RICOH COMPANY, LTD.

#### Electronic Devices Company

##### ● Higashi-Shinagawa Office (International Sales)

3-32-3, Higashi-Shinagawa, Shinagawa-ku, Tokyo 140-8655, Japan  
Phone: +81-3-5479-2857 Fax: +81-3-5479-0502

### RICOH EUROPE (NETHERLANDS) B.V.

#### ● Semiconductor Support Centre

Prof. W.H.Keesomlaan 1, 1183 DL Amstelveen, The Netherlands  
P.O.Box 114, 1180 AC Amstelveen  
Phone: +31-20-5474-309 Fax: +31-20-5474-791

### RICOH ELECTRONIC DEVICES KOREA Co., Ltd.

11 floor, Haesung 1 building, 942, Daechidong, Gangnamgu, Seoul, Korea  
Phone: +82-2-2135-5700 Fax: +82-2-2135-5705

### RICOH ELECTRONIC DEVICES SHANGHAI Co., Ltd.

Room403, No.2 Building, 690#Bi Bo Road, Pu Dong New district, Shanghai 201203,  
People's Republic of China  
Phone: +86-21-5027-3200 Fax: +86-21-5027-3299

### RICOH COMPANY, LTD.

#### Electronic Devices Company

##### ● Taipei office

Room109, 10F-1, No.51, Hengyang Rd., Taipei City, Taiwan (R.O.C.)  
Phone: +886-2-2313-1621/1622 Fax: +886-2-2313-1623



Ricoh completed the organization of the Lead-free production for all of our products. After Apr. 1, 2006, we will ship out the lead free products only. Thus, all products that will be shipped from now on comply with RoHS Directive.